1984 Index to Quality Progress and Journal of Quality Technology

Subjects

Computers

Berger, Roger L.—*Looking for Software?* QP Mar., p. 28.
Campanizzi, J.A.—*Structured Software Testing,* QP May, p. 14.
Carpenter, C.L. and Gerald E. Murine—*Measuring Software Product Quality,* QP May, p. 16.
Directory of Software for Quality Assurance and Quality Control, QP Mar., p. 33.
Guide to Software Products, QP Mar., p. 30.
Ryan, John M. and Herbert Wong—*Tiered Data Systems for Statistical Quality Control,* QP Sept., p. 22.

Education

Clegg, William H.—*Making the Move from Industry to Academia,* QP Mar., p. 16.
Zimmerman, D. Kent—*Management Courses: Are They Overlooking Quality,* QP May, p. 26.

Employment

Sullivan, Edward—*Electronics Managers See Changes in Quality Field,* QP July, p. 32.

Energy

Burns, Robert G.—*Is NRC's QA Program Working?—Quality Paradoxes Cloud NRC Successes,* QP Jan., p. 29.
Hull, B. Jeanine—*Is NRC's QA Program Working?—NRC Must Make Top Management Accountable for Quality,* QP Jan., p. 29.
Kirschenmann, Harley J.—*Management Attitudes Toward Quality Assurance,* QP Jan., p. 34.
McDonald, Marshall—*Commitment to Success at FPL,* QP Jan., p. 26.

Group Testing

Hwang, F.K.—*Robust Group Testing,* JQT Oct., p. 189.
Mundel, A.B.—*Group Testing,* JQT Oct., p. 181.

Human Factors

Labor's Role in Quality, QP Aug., p. 25.
Rubinstein, Sidney P.—*Quality Control Requires a Social and Technical System,* QP Aug., p. 22.

Inspection

Zuech, Nello—*Machine Vision Inspection—Pragmatically Speaking,* QP May, p. 36.

Management

Boileau, Oliver C.—*Improving Quality and Productivity at General Dynamics,* QP Aug., p. 16.
Burr, I.W.—*Management Needs to Know Statistics,* QP July, p. 26.
Dorsky, Lawrence R.—*Management Commitment—To Japanese Apple Pie,* QP Feb., p. 14.
Hagan, John T.—*The Management of Quality: Preparing for a Competitive Future,* QP Oct., p. 44, QP Nov., p. 12, and QP Dec. p. 21.
Hancock, Geoffrey—*Quality Brings Sales Dividends to Jaguar,* QP May, p. 30.
Harwood, Charles C.—*The View from the Top,* QP Oct., p. 26.
Johnson, Gary—*Chasing Quality Problems,* QP Oct., p. 57.
Mozer, Clark—*Total Quality Control: A Route to the Deming Prize,* QP Sept., p. 30.
Patch, Stuart F.—*Using Quality Improvement to Increase Market Share,* QP Apr., p. 16.
Pavsidis, Constantine—*Total Quality Control: An Overview of Current Efforts,* QP Sept., p. 28.
Schonberger, Richard J.—*Just-in-Time Production—The Quality Dividend,* QP Oct., p. 22.
Stalter, Joe—*Process in Control for Conformance,* QP Apr., p. 18.
Sullivan, L.P.—*Reducing Variability: A New Approach to Quality,* QP July, p. 15.
Traver, Robert W.—*Locating the Key Variable(s),* QP Feb., p. 21.

Motivation

Ambali, Jayaprakash and Kripa Shanker—*QC Circles in Japan: What Keeps Them Going?* QP Oct., p. 52.
Cornell, Leonard—*Quality Circles in the Service Industries,* QP July, p. 22.

Perspectives

Müller, Frank W.—*Assuring Quality in Development and Design: An Antithetical Approach,* QP Sept., p. 18.

Profit/Cost

Williams, Harry E.—*Quality Plus Productivity Plus Cost Equals Profit,* QP Oct., p. 17.

QP Special Feature

National Quality Month: Resolution, Proclamation, Appreciation, QP Nov., p. 8.
Quality First: A National Campaign to Promote Quality, QP Sept., p. 14.
Quality Month Resolutions Introduced, QP Aug., p. 9.
The State of Quality in the U.S. Today: A.V. Feigenbaum, J.M. Juran, and Philip B. Crosby, QP Oct., p. 32.
The State of Quality in the U.S. Today: James M. Beggs on Quality, Productivity, and NASA, QP Oct., p. 40.
The State of Quality in the U.S. Today: Supplier Quality Improvement, QP Oct., p. 48 and Dec. 35.

Quality Motivation

Tribett, C.W. and R.J. Rush—*Theories of Motivation: A Broader Perspective,* QP Apr., p. 38.

Reliability

Bankaitis, H.—*Reliability and Quality Assurance in Research and Development,* QP Mar., p. 10.
Smith, E.—*Long Life on the Lunar Surface: The Payback of Front-End Quality,* QP, Dec., p. 16.

Sampling

Bryson, M.C.—*Sample Size Determination—Revised and Simplified,* QP Dec., p. 40.
Chou, Youn-Min and D.B. Owen—*One-Sided Confidence Regions on the Upper and Lower Tail Areas of the Normal Distribution,* JQT July, p. 150.
Cross, Robert—*Parts Per Million AOQL Sampling Plans,* QP Nov., p. 29.
Jaech, John L.—*Removing the Effects of Measurement Errors in Constructing Statistical Tolerance Levels,* JQT Apr., p. 69.
Mee, Robert W.—*Tolerance Limits and Bounds for Proportions Based on Data Subject to Measurement Error,* JQT Apr., p. 74.
Manzefricke, Ulrich—*The Effects of Variability in Inspection Error,* JQT July, p. 131.
Pugh, G. Allen and Joseph I. Elgomayel—*Generating a Set of Interrelated Inspection Sampling Plans,* JQT Jan., p. 39.
Riew, Moon Charn and Do Sun Bai—*An Economic Attributes Acceptance Sampling Plan With Three Decision Criteria,* JQT July, p. 136.
Schilling, Edward G.—*An Overview of Acceptance Control,* QP Apr., p. 22.

Selection

Wilcox, Rand R.—*A Table for Rinott's Selection Procedure,* JQT Apr., p. 97.

Shewhart Medal Address

Ishikawa, Kaoru—*Quality and Standardization: Program for Economic Success,* QP Jan., p. 16.
Schilling Edward G.—*The Role of Statistics in the Management of Quality,* QP Aug., p. 32.

Society

Maas, Robert R., Eddie F. Thomas, and John L. Hansel—*ASQC: Prelude to New Growth,* QP July, p. 12.
QualTest Grows in Second Year, QP Jan., p. 22.
Ryan, John—*Annual Quality Congress Highlights,* QP Aug., p. 52.

Statistics

Canavos, George C. and Ioannis A. Koutrouvelis—*The Robustness of Two-Sided Tolerance Limits for Normal Distributions,* JQT July, p. 144.
Carlsson, Olle—*Determining the Most Profitable Process Level for a Production Process Under Different Sales Conditions,* JQT Jan., p. 44.
Cohen, A. Clifford, Betty Jones Whitten, and Yihua Ding—*Modified Moment Estimation for the Three-Parameter Weibull Distribution,* JQT July, p. 159.
Cornell, John A. and John W. Gorman—*Fractional Design Plans for Process Variables in Mixture Experiments,* JQT Jan., p. 20.
Hahn, G.J. and W.Q. Meeker—*An Engineer's Guide to Books on Statistics and Data Analysis,* JQT Oct., p. 196.
Hall, Irving J.—*Approximate One-Sided Tolerance Limits for the Difference or Sum of Two Independent Normal Variates,* JQT Jan., p. 15.
Mandel, John—*Fitting Straight Lines When Both Variables are Subject to Error,* JQT Jan., p. 1.
St. John, Ralph C.—*Experiments with Mixtures, Ill-Conditioning, and Ridge Regression,* JQT Apr., p. 81.

Technology

Drews, Richard E.—*Remote Automatic Calibration—The Future Today,* QP Aug., p. 28.
Dunn, A.G.—*Considering Robots?* QP June, p. 10.
Evans, David H.—*Quality Control and Robotic Assembly,* QP June, p. 62.
Everhart, F.J. and K. Sateesh—*The Factory with a Future—A Closer Look,* QP June, p. 21.
Gingerich, J.Z. and J.W. Peery—*CAD/CAM and Quality,* QP June, p. 8.
Langevin, R.G.—*Getting Quality Ready for the Factory of the Future,* QP June, p. 54.
Lowery, Andrew—*Automated Production and QA Systems for Medical Devices,* QP June, p. 58.
McArthur, C. Daniel—*Automation, JIT Inventory Systems and Quality,* QP June, p. 64.
Melan, E.H., R.T. Curtis, and G.A. Snyder—*Quality Data Systems in Semiconductor Manufacturing,* QP June, p. 32.
Nash, W.L. and F.M. Webster—*Machine Vision Systems Today—and Tomorrow,* QP June, p. 13.
The NBS Automated Manufacturing Research Facility, QP June, p. 48.
Owens, D.A.—*The Factory with a Future—An Overview of One Automated Factory,* QP June, p. 18.
Preston, R.R. and R.H. Wettach—*A Look Into the Future: The Air Force View,* QP June, p. 40.
Ryan, John—*Integrated Quality Database Management Systems,* QP June, p. 29.
—*Whither $\bar{x}$? Statistics in the Factory of the Future,* QP June, p. 56.
Schaffer, George—*Computer-Aided Inspection and Reporting,* QP June, p. 26.

Testing

Burchett, Gerald—*Testing Test Equipment,* QP April, p. 34.

Trends

Ryan, John—*Controlling Static—New Solutions to an Old Problem,* QP Apr., p. 27.

Tutorial

Kindlarski, E.—*Ishikawa Diagrams for Problem Solving,* QP Dec., p. 26.

Vendor-Vendee

Brush, G.G., T.C. Hsiang, W. McKeown and T. Rogers—*After the Bell System Break Up: Supplier Quality at Bellcore,* QP Nov., p. 16.
Cherry, J.V.—*Vendor's Viewpoint: Quality, Response, and Delivery,* QP Nov., p. 40.
Cloer, W.C.—*Objective: Zero Defects Suppliers,* QP Nov., p. 20.
Barker, Eugene M.—*Counting Costs: Another Approach to Supplier Ratings,* QP Nov., p. 67.
Burgess, John A.—*RIP: A Rejection Improvement Program,* QP Nov., p. 70.
Connell, Gale W.—*Quality at the Source: The First Step in Just-in-Time Production,* QP Nov., p. 40.
Feldman, Allen W.—*Vendor Quality Rating and Customer Perception,* QP Nov., p. 64.
Johnson, Bob—*Just-in-Time Deliveries Through Vendor Self-Inspection,* QP Nov., p. 46.
Laford, Richard J.—*Ship to Stock,* QP Nov., p. 52.
Murakami, Kishii, and Inamura—*PPM Control for Electronic Parts,* QP Nov., p. 25.
Pennucci, Nicholas J.—*Assuring Vendor Process Control to Reduce Incoming Sampling,* QP Nov., p. 56.
Pettit, Robert H.—*Vendor Evaluation Made Simple,* QP March, p. 19.
Richardson, John C.—*Vendor Quality Assurance in a Process Industry,* QP Nov., p. 60.
Tolan, Thomas—*Provider Quality: Long Distance Inspection,* QP Nov., p. 74.
Ware, Paul A.—*A Cooperative Approach to Vendor Certification,* QP Nov., p. 36.

Authors

See the subject categories after each author's name for articles. Co-authored articles are listed in subject categories by the author whose name comes first alphabetically.

Ambali, Jayaprakash, Motivation

Bai, Do Sun, Sampling (see Riew)
Bankaitis, H., Reliability
Barker, Eugene M., Vendor-Vendee
Beggs, James M., QP Special Feature
Berger, Roger L., Computers
Boileau, Oliver C., Management
Brush, G.G., Vendor-Vendee
Bryson, M.C., Sampling
Burchett, Gerald, Testing
Burgess, John A., Vendor-Vendee
Burns, Robert G., Energy
Burr, I.W., Management

Campanizzi, J.A., Computers
Canavos, George C., Statistics
Carlsson, Olle, Statistics
Carpenter, C.L. (Skip), Computers
Cherry, J.V., Vendor-Vendee
Chou, Youn-Min, Sampling
Clegg, William H., Education
Cloer, W.C., Vendor-Vendee
Cohen, A. Clifford, Statistics
Connell, Gale W., Vendor-Vendee
Cornell, John A., Statistics
Cornell, Leonard, Motivation
Crosby, Philip B., QP Special Feature
Cross, Robert, Sampling
Curtis, R.T., Technology (see Melan)

Ding, Yihua, Statistics (see Cohen)
Dorsky, Lawrence R., Management
Drews, Richard E., Technology
Dunn, A.G., Technology

Elgomayel, Joseph I., Sampling (see Pugh)
Evans, David H., Technology
Everhart, F.J., Energy

Feigenbaum, A.V., QP Special Feature
Feldman, Allen W., Vendor-Vendee

Gingerich, J.Z., Technology
Gorman, John W., Statistics (see Cornell)

Hagan, John T., Management
Hahn, G.J., Statistics
Hall, Irving J., Statistics
Hancock, Geoffrey, Management
Hansel, John L., Society (see Maas)
Harwood, Charles C., Management
Hsiang, T.C., Vendor-Vendee (see Brush)
Hull, B. Jeanine, Energy
Hwang, F.K., Group Testing

Inamura, Vendor-Vendee (see Murakami)
Ishikawa, Kaoru, Shewhart Medal Address

Jaech, John L., Sampling
Johnson, Gary, Management
Johnson, Bob, Vendor-Vendee
Juran, J.M., QP Special Feature

Kindlarski, E., Tutorial
Kirschenmann, Harley J., Energy
Kishii, Vendor-Vendee (see Murakami)
Koutrouvelis, Ioannis A., Statistics

Laford, Richard J., Vendor-Vendee
Langevin, R.G., Technology
Lowery, Andrew, Technology

Maas, Robert R., Society
Mandel, John, Statistics
McArthur, C. Daniel, Technology
McDonald, Marshall, Energy
McKeown, W., Vendor-Vendee (see Brush)
Meeker, W.Q., Statistics (see Hahn)
Mee, Robert W., Sampling
Melan, E.H., Technology
Menzefricke, Ulrich, Sampling
Mozer, Clark, Management
Müller, Frank W., Perspectives
Mundel, A.B., Group Testing
Murine, Gerald E., Computers (see Carpenter)
Murakami, Vendor-Vendee

Nash, W.L., Technology

Owen, D.B., Sampling (see Chou)
Owens, D.A., Technology

Patch, Stuart F., Management
Pavsidis, Constantine, Management
Peery, J.W., Technology (see Gingerich)
Pennucci, Nicholas J., Vendor-Vendee
Pettit, Robert H., Vendor-Vendee
Preston, R.R., Technology
Pugh, G. Allen, Sampling

Richardson, John C., Vendor-Vendee
Riew, Moon Charn, Sampling
Rogers, T., Vendor-Vendee (see Brush)
Rubinstein, Sidney P., Human Factors
Rush, R.J., Quality Motivation (see Tribett)
Ryan, John, Society, Technology, Trends
Ryan, John, Computers

Sateesh, K., Technology (see Everhart)
Schaffer, George, Technology
Schilling, Edward G., Sampling, Shewhart Medal Address
Schonberger, Richard J., Management
Shanker, Kripa, Motivation (see Ambali)
Smith, E., Reliability
Snyder, G.A., Technology (see Melan)
St. John, Ralph C., Statistics
Stalter, Joe, Management
Sullivan, Edward, Employment
Sullivan, L.P., Management

Thomas, Eddie F., Society (see Maas)
Tolan, Thomas, Vendor-Vendee
Traver, Robert W., Management
Tribett, C.W., Quality Motivation

Ware, Paul A., Vendor-Vendee
Webster, F.M., Technology (see Nash)
Wettach, R.H., Technology (see Preston)
Whitten, Betty Jones, Statistics (see Cohen)
Wilcox, Rand R., Selection
Williams, Harry E., Profit/Cost
Wong, Herbert, Computers (see J.M.Ryan)

Zimmerman, D. Kent, Education
Zuech, Nello, Inspection

Book Reviews

Books with multiple authors are listed under whichever author comes first alphabetically.

Blanchard, K. and S. Johnson, *The One Minute Manager*, QP Oct., p. 12.
Carter, Walter H., Jr., Galen L. Wampler, and Donald M. Stublein, *Regression Analysis of Survival Data in Cancer Chemotherapy*, JQT Jan., p. 68.
Chambers, J., W. Cleveland, B. Kleiner, and P. Tukey, *Graphical Methods for Data Analysis*, JQT July, p. 177.
Criner, E.A., *Successful Cost Reduction Programs for Engineers and Managers*, QP Oct., p. 12.
Crosby, Philip B., *Quality Without Tears*, QP Oct., p. 10.
Dhillon, Balbir S., *Reliability Engineering in Systems Design and Operation*, QP May, p. 12.
Dixon, W.J. and F.J. Massey, Jr., *Introduction to Statistical Analysis*, 4th edition, JQT Apr., p. 127.
Enrick, Norbert L. with Harry E. Mottley, *Manufacturing Analysis for Productivity and Quality/Cost Enhancement*, 2nd edition, QP Apr., p. 8.
Feigenbaum, Armand V., *Total Quality Control*, JQT July, p. 178.
Graham, Nancy O., *Quality Assurance in Hospitals; Strategies for Assessment and Implementation*, QP Oct., p. 10.
Hicks, Charles R., *Fundamental Concepts in the Design of Experiments*, 3rd edition, JQT Jan., p. 67.
Hunker, Jeffrey Allen, *Structural Change in the U.S. Automobile Industry*, QP Sept., p. 10.
Kateman, C. and F.W. Pijpers, *Quality Control in Analytical Chemistry*, JQT Jan., p. 66.
Montgomery, Douglas C., *Design and Analysis of Experiments*, 2nd edition, QP Sept., p. 10.
Morrison, Donald F., *Applied Linear Statistical Methods*, JQT Oct., p. 240.
Ott, Lyman and David K. Hildebrand, *Statistical Thinking for Managers*, JQT Apr., p. 127.
Parker, Sybil, ed., *McGraw-Hill Concise Encyclopedia of Science and Technology*, JQT Oct., p. 240.
Salsburg, David, *Understanding Randomness*, JQT Apr., p. 128.
Spotts, M.F., *Dimensioning and Tolerancing for Quality Production*, QP May, p. 12.
Tufte, Edward R., *The Visual Display of Quantitative Information*, JQT July, p. 177.
Wheatley, Edward W., *Marketing Professional Services*, QP Sept., p. 10.

Computer Programs

The following subjects may be located in issues of the *Journal of Quality Technology*.

Determination of Rectifying Inspection Plans for Single Sampling by Attributes, William C. Guenther, Jan., p. 56.
Machine Setting to Minimize Scrap and Rework Costs, Carl R. Lindenmeyer, E. Earl Burch, Jr., and Henry W. Andrews, Apr., p. 121.
Normal Family Distribution Functions: FORTRAN and BASIC Programs, R.J. Craig, Oct., p. 232.
Wald Sequential Sampling for Attribute Inspection, David R. Garrison and John J. Hickey, July, p. 172.

Standards & Specifications

The following subjects may be located in issues of the *Journal of Quality Technology*.

Guide for Selection of an Acceptance Sampling Plan, A. Blanton Godfrey and August B. Mundel, Jan., p. 50.
The Performance of ANSI/ASQC Z1.9-1980 Under the Switching Rules, E.G. Schilling and J.H. Shessley, Apr., p. 101.
Small Acceptance Number Plans for Use in Military Standard 105D, B.S. Liebesman and F.C. Hawley, Oct., p. 219.
Which Sampling Plan Should I Choose? John W. Enell, July, p. 168.

Technical Aids

The following subjects by Lloyd S. Nelson may be located in issues of the *Journal of Quality Technology*.

Display Tables and Significant Digits, July, p. 175.
The Shewhart Control Chart—Tests for Special Causes, Oct., p. 237.
Simplified Critical Values for the Sign Test, Apr., p. 125.
Some Notes on Student's t, Jan., p. 64.